

Notice of References Cited

Application/Control No.

10/585,875

Applicant(s)/Patent Under
Reexamination
OGINO ET AL.

Examiner

Edu E. Enin-Okut

Art Unit

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,128,700	12-1978	Sederquist, Richard A.	429/17
*	B	US-2002/0031450	03-2002	YAMASHITA et al.	429/17
*	C	US-5,441,821	08-1995	Merritt et al.	429/17
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000195534 A	07-2000	Japan	AOYAMA, SATOSHI	H01M 8/06,3/38,8/04
	O	JP 10144335 A	05-1998	Japan	IKEDA et al.	H01M 8/06,8/04
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"ammeter." Merriam-Webster Online Dictionary. Accessed on November 23, 2009 from < http://www.merriam-webster.com/dictionary/ammeter >.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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